# 平面顯示技術概論 平面顯示器製程設備



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Process Equipment Development for TFT-LCD Manufacturing

# YT Kuo ( 郭怡之 )

# **AKT, an Applied Materials Company**

Dec. 21, 2005





- Introduction to AKT
  - AKT's history & present
- TFT-LCD Technology
  - Investor's Point of View
- Technologies of AKT
  - Plasma-enhanced chemical vapor deposition (PECVD) process system
  - Process Capability
  - Electron Beam array Tester
- Challenges and solutions to the large-size substrate processing





# **AKT Overview**









# **Applied Materials**

- Founded: 1967
- Employees: 13,000
- Net Sales FY04: \$8B
- Manufactures systems for processing silicon wafers, Flat Panel Displays, Mask Pattern Generation, Etch & Inspection Systems, and designs software for semiconductor manufacturing



- Founded: 1993
- Employees: ~ 450
- Manufactures systems for
   Flat Panel Display
   production, with processing
   glass substrate up to ~
   2100x2400 mm<sup>2</sup>







**AKT Mission Statement** 

<u>акт</u>

"Be the Leading Supplier of Display Manufacturing Equipment and Service through Innovative Technology and Continuous Improvement of Products Enhancing Customers' Productivity."



# **Company History**



Started PE-CVD Development in AMAT – ADT	19	91
Joint development program with Japan	1992	-1993
Shipped the first AKT-1600 CVD to Japan	Feb.	1993
Formed 50:50 JV Applied Komatsu Technology	Sep.	1993
Established AKT Korea Branch	Мау	1994
Shipped first AKT-1600 CVD to Korea	Sep.	1994
Shipped the first system to Taiwan	Feb.	1996
AMAT bought 50% share from Komatsu	Oct.	1999
Established AKT Taiwan Branch	Dec.	1999
Acquired EBT organization in Germany	Jan.	2000
Shipped the 400 <sup>th</sup> PECVD system to China	Sep.	2004
Opened 1st AKT office in P.R. China	Sep.	2004
450 <sup>th</sup> PECVD system shipped	May.	2005



# **AKT's Current Focus**

# **Products**



Gen 8 PECVD -System / Process Development -Beta System Manufacturing

### <u>Gen 6 – 7.5 PECVD</u>

-Fab start-up/Production Support

### Gen 2 - 4 PX PECVD for LTPS -

-Process Enhancement -R&D/Production Support

### **Gen 6 - 7 EBT (Array Tester)**

-Fab start-up/Production Support

### **Gen 8 EBT (Array Tester)**

-Concept Design



# Technology



### **Continuous Development**

- -Throughput Enhancement -COO Reduction -Innovative Future Technology & Product Development -PECVD:
- -a-Si / LTPS Superior Process -Lower Chamber Cleaning Cost -Particle Reduction -Low Temperature Deposition -EBT:

-Detectability Enhancement -IPS / LTPS / OLED Test Capability

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# **Customer Support**

(E)) A K T



# **Global Focus**

-Rapid and Smooth Start-Up -On-time Spare Parts Delivery -Productivity Improvement -Post-Warranty Contracts -Total Support Package -Used System Support -Customer Training -Local Manufacturing Capability AKT Systems Installation Base (As of Q4/FY 2005 End - Estimation)



### Taiwan 208 Japan 163 CVD 480 157 18 Korea PVD US & EU 15 13 Etch China EBT 33 5 546 Total **546** Total 480th PECVD shipped in Oct 2005

AKT's products are used for mass production at major LCD fab's in the world



# **AKT Worldwide Locations for Customer Support**



# **United States**

### Santa Clara

- RD& E
- Manufacturing
- Engineering
- Customer Demo Facility
- Product Marketing
- Strategic Marketing
- Product Support & Training
- Spare Parts

# Germany (AKT EBT)

### Feldkirchen

- Engineering \_
- Manufacturing Array Tester



# **Korea**

Kihueng

Chonan

– Kumi

### Seoul

- Sales
- Customer
- Service Center
- Spare Parts
- Tangjung - Product Support Paiu



- Osaka
- Sales and Marketing
- Customer Service Center

### Tokyo

Customer Service Center

### Service Offices

- Tokyo
- Osaka

### China

### Beijing

 Sales and Service Spares Depot: Beijing Service office: Beijing

# Japan





## **Taiwan**

### Hsin-Chu

 Sales and Service Spares Depot: Taoyuan Service office: Tainan Taichung





**AKT** Taiwan Summary

- Formed in 1996 under Applied Materials Taiwan
- Legal Entity established in 1999
- Basin Hsinchu main office and 3 site offices
  - Taoyuan (spare operations, 2000)
  - Taichung (2004)
  - Tainan (2000)
- YTD: 60 RFT and 35 contractors.



- More than 200 AKT systems Installed in Taiwan by August '05.
- Asia R&D Center (ARDC) established in Taiwan in 2004



# **AKT** Taiwan Offices





- Close proximity to all customers in Asia
  - Fast demo cycles and lower cost
  - Rapid testing & implementing of continue improvement programs to customers
  - Close to customers eager for new technology demo & beta-site test
- Strategic partnership with ITRI
  - Exploiting ERSO processing capability for TFT device characteristics study and advanced technology
  - Exploiting MIRL's precision machinery engineering capability for future machine parts/ modules/ sub-system OEM/ ODM manufacturing, which provide high quality, lower cost, fast deliver speed to support all customers in Asia
  - Close collaboration with ERSO for Join Develop program- AM, AdOx, pass-SiN,.. etc.
  - Utilizing ITRI's overall advanced capabilities





- Intending to cover all R&D areas which may generate significant technology advancement and/or productivity enhancement
- Focusing on TFT-LCD sector, while vigilantly monitoring other emerging sectors (e.g., OLED, FED, etc.)
- Leveraging existing strong R&D resources, manufacturing experiences and global intelligence network in Taiwan
  - Advanced process capabilities
  - Advanced integration capabilities
  - Advanced testing / analysis capabilities
- Large cleanroom space in ITRI for multiple projects
  - Large area substrate processing capability Gen 5, Gen 6 and beyond
  - Both wet and dry processing capability



# R&D focus

- Large area substrate processing
- Advanced CVD process technology
- Advanced metalization technology
- Other innovative new applications
- Joint research force AKT and ITRI
  - Talented engineers
    - Hardware engineers
    - Software engineers
    - Process engineers
    - System engineers
  - Versatile technicians
- Located inside ITRI close proximity to ERSO
- Facilities and Equipments jointly provided by ITRI and AKT



# **ARDC - Facilities & Projects**

<u>ер АКТ</u>

- Process tool

   -15KA (Gen.5) Test
   Stand
- Measurement tools
  - Stress meter
  - FTIR
  - RI/thickness
  - Digiscreen
  - Alpha step
- Glass cutter
- Resources in ERSO
  - WER
  - Ellipsometry
  - SEM/EDX
  - CV
  - Device

- Thin film processes
  - Cleaning process cost reduction
     a. Feasibility of F2 recycling
     b. NF3 usage optimization
  - LC alignment layer process
- Automation parts refurbishment
  - Vacuum robot refurbishment
- Parts localization
  - 1600 Process chamber
  - E-gun



# **ARDC - Photos**



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# **AKT Santa Clara Campus**

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- January, 1996 AKT occupied 170,000 ft<sup>2</sup> (15,800 m<sup>2</sup>) campus
- Manufacturing & Spare Center
  - 12 Manufacturing Final Test Bays
- Engineering Lab Space:
  - 9 R&D Product / Process Development Bays
  - 4 R&D Product Development/Reliability (Mfg type) Bays
  - Mechanical Reliability, Wet Chemistry Lab, Analytical/Metrology Lab, and Other

Engineering Labs

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the Future



# LCD & TFT-LCD











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Large-size LCD-TV is booming ...

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# 65" LCD-TV – SHARP 82" LCD-TV – SAMSUNG





And more new applications ....

# Philips Chameleon Mirror-Display



# ?? Even in WC ??





<u>AKT</u>



and they're coming to Taiwan ...



# 新聞中心

Date: 2005年4月26日

友達啓動次世代投資計劃基板尺寸1950mm x 2250mm

月產能規劃三萬片投資金額將達350億

- (2005年4月26日)

友達廠房 (世代)	玻 璃基板尺(mm)	地點	主要產品
L3A (G3.5)	610 x 720	新竹科學園 區	中小尺寸/筆記型電腦面板
L3B (G3.5)	610 x 720	新竹科學園 區	中小尺寸
L5 (G3.5)	600 x 720	新竹科學園 區	桌 /筆記型電腦面板
L6 (G4.0)	680 x 880	龍潭渴望園 區	筆記型電腦/電視面板
L8A (G5.0)	1100 x 1250	龍潭渴望園 區	桌 / 電視面板
L8B (G5.0)	1100 x 1300	龍潭渴望園 區	桌 /筆記型電腦/電視面板
L8C (G5.0)	1100 x 1300	中部科學園 區	桌 /筆記型電腦
L10 (G6.0)	1500 x 1850	中部科學園 區	桌 / 30~40 时 板
L11 (G7.5)	1950 x 2250	中部科學園 區	40 时 以上電視面板

### 奇美電:第二季成長5-10% 首季EPS-0.52元 宣布再擴建1座5代廠 並 跨入7.5代面板廠

### 【王宗彤 / 台北報導】

奇美電(3009)昨公布第一季季報,營收為267.01億元,稅後淨損19.71億元,每股稅後淨損0.52元。另外,奇美電也宣布投入次世代生產線,包括再投資新台幣200億元,將現有5.5代面板廠月投片量由原訂12萬片提升至18萬片,以及投資350億元再擴建1座5代廠,並跨入7.5代面板廠投資。

同時,**奇美**電預估第二季出貨量較第一季成長5-10%,ASP微幅上揚或持 平,成本下滑5-10%,今年全年TFT-LCD景氣為審慎趨樂觀。

**奇美**電財務處長陳彥松表示,為因應新投資案需求,**奇美**電今、明兩年資本支出各約達700億元,除將動撥金融機構聯貸額度支應外,今年股東會也將 提出私募特別股及辦理現金增資兩項籌資案。

奇美電是繼友達(2409)日前宣布7.5代面板廠投資案後,為台灣第二家面 板廠宣布跨入更新次世代生產線,奇美電預計今年6月進行7.5代面板廠土建 工程,預計2007年第二季投產,初期投片量為每月3萬片基板產能。

奇美電5.5代面板廠原投資金額750億元,昨宣布再投資200億元將投片量 提高至18萬片後,5.5代廠總投資金額將提高至950億元。奇美 電決定再投資 一座5代廠,該廠廠房將在下週起進行土建工程,預計 2006年第二季移入設 備、第四季量產。

陳彥松並宣布 7.5代廠建廠計劃重新啟動,原以停建的廠房硬體工程將在 下周復工,首期投片量為3萬片,預計量產時點比5代新廠量產晚6個月,將在 2007年第2季量產,以生產42吋及47吋TV面板。**奇美**電總經理何昭陽表示,**奇** 美電認為LCD TV市場已起來,目前正是擴充的大好時機?

From: China Times, April 30, 2005



# **Taiwan TFT-LCD Manufacturers**



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# **Growth of Substrate Area**

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• Why TFT-LCD Manufacturers always Invest New Generation Size?

- New application requires larger size, such as LCD-TV
- LCD-TV, a consumer product competing with conventional CRT & other FPD TVs, needs faster Price reduction to gain the market share. <u>Larger</u> <u>size which means new generation brings the cost down more</u> <u>feasible</u>.



# **Rapid Growth of Substrate Size**

6 up 46.0" Wide panels

<u> AKT</u>





# **Investment vs. Substrate size**

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Gen	Glass Size	Area (m2)	Area Increase	Equipment	Facilities Land	Total Investment	Investment Increase
5	1100 × 1300	1.43	100%	\$887	\$577	\$1,464	100%
6	1500 × 1850	2.78	194%	\$1,180	\$802	\$1,982	135%
7	1870 × 2200	4.11	288%	\$1,362	\$926	\$2,288	156%
7.5	2160 × 2460	5.31	372%	\$1,808	\$1,229	\$3,037	207%

Note: 60,000 substrates per month fab, 5-mask process. Equipment includes array, cell, color filter and module tools. Actuals will vary significantly by process type, manufacturer, timing, location, etc. Indexed to G5.

Ref: 7th Annual DisplaySearch US FPD Conference, Charles Annis, page 16, w/ permission





Note : Forecast 32" WXGA LCD TV "Total Sales Cost" of \$720.1 for G4 to \$598.8 for G7 in 2005. "Others" includes Personnel, Indirect, R&D, and Overhead/Sales expenses.

Ref: 7th Annual DisplaySearch US FPD Conference, Charles Annis, page 17, w/ permission



# **Cost Of Ownership Modeling**

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ITEM	<u>units</u>		SYSTEM
Number of Chambers			5
System Price	\$		400,000,000
System Quantity			1
Throughput			48
Gross Throughput		sub/mon	34,560
Adjustments To Throughput:			
System Uptime		%	85%
Line Yield rate		%	99.5%
Net Yearly Capacity (not incl. yield)		subs/mon.	29,376
Net Yearly Capacity (incl. yield.)		subs/mon.	29,229
Fixed Costs			
Equipment Depreciation	\$	/mon	6,666,667
Incidental EQ cost: ACLS			9,091,500
Pump			13,800,000
Local Scrubber			4,350,000
Insurance Cost: Main EQ shipping ins. cost			121,000
Cleanroom (Floorspace) Depreciation	\$	/mon	116,451
Total Fixed Costs	\$	/mon.	7,161,472
Fixed Costs/ per sub.	\$	/sub	245.01
Variable Costs			
Consumable Parts (Average)	\$	/mon.	300,000
PM Kit for system and PC	\$	/mon.	201,331
Electrical/Utility	\$	/mon.	919,670
Process Gases	\$	/mon.	672,417
Clean Gases	\$	/mon.	1,739,353
Labor cost	\$	/mon.	58,676
Total Variable Costs	\$	/mon.	3,891,446
Variable Costs/ per sub.	\$	/sub	133.14
Total Cost of Operation	\$	/yr.	11,052,918
Cost Per Substrate (By EQ process capacity )	\$	/sub	378.15





# For equipment suppliers, **Production Worthiness** is the key.

- System throughput depends on both process time and mechanical transfer, and the latter gets more significant.
- Down time reduction for higher productivity requires better system reliability and easier & more flexible service (PM); against the increasing chamber size and weight.







# Technologies of AKT

# Plasma Enhanced Chemical Vapor Deposition (PECVD)


**AKT PECVD** Development Concept

### **Development Key Strategy**

### LOW RISK & QUICK DEVELOPMENT

Field proven System Construction The First Introduced to Industry

**AKT PECVD** 

### **PROCESS QUALITY**

Reliable Process Scale Up & Development

### RELIABILITY

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Reliable Substrate Handling Compensate Thermal Expansion

### **CAPITAL PRODUCTIVITY**

Minimize <u>Cost of Ownership</u> Small Foot Print Cluster Tool System HW Throughput ≥ 65 sub / hr



# Single Substrate, Multi-Process Chamber Cluster Tool 🖳 AKT





## **AKT PECVD System Configuration**





## AKT PECVD Cluster Tool Advantages

### Higher Performance

- Single loadlocked vacuum environment for multiple films
- High throughput through batch
  pumpdown and pre-heat
- High throughput using up to 5~6 process chambers in parallel



### **Compared to Inline Tools**

- Small system footprint
- Does not require trays
- Horizontal substrate handling avoids edge rubbing and reduces particle
- Higher system uptime and quicker maintenance



## AKT PECVD Cluster Tool System Control

A K T











## **AKT-15K PECVD DDSL**

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### **Capacitively-Coupled Parallel Plate Plasma Reactor**



## Remote Plasma Source (RPS) Chamber Cleaning

- Used to clean deposited film residues from process chamber components
- RPS <u>fully</u> dissociates cleaning gas remotely from process chamber:

 $NF_3 \rightarrow N_2 + F$ 

- Active species (F radicals) directed to process chamber where cleaning reaction occurs: F + Si → SiF<sub>4</sub>
- Extends lifetime of chamber components, reduces cost-of-ownership
- Environmental friendly Green Technology



In situ plasma cleaning

 $NF_3 / (CxFy + O_2) / ... + Si / SiNx / SiO_x + RF plasma -> SiF_4 \uparrow + ...$ 

Productivity greatly improved, but potential plasma damage to chamber parts, and the cleaning gas not fully utilized.

Remote Plasma Source Cleaning (RPSC)

NF<sub>3</sub> + remote plasma (RPS) ->N<sub>2</sub> + F; F + Si / SiN<sub>x</sub> / SiO<sub>x</sub> -> SiF<sub>4</sub>  $\uparrow$  + ...

#### Further improved yield and productivity;

- Reduced Cost of Ownership (COO) with extended chamber parts lifetime;
- Clean gas dissociation > 97%
  virtually full utilization
  and environmental friendly





## Gen.7 AKT-40K PE-CVD System



### Handling 1.87x2.2m<sup>2</sup> Substrate



# AKT-40K PECVD System





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# **AKT PECVD Process Capability**



## g-SiN<sub>x</sub> Applications and Advantages

### **Process Performance**

Deposition Rate Thickness Non-Uniformity Refractive Index Stress Wet Etch Rate Breakdown Voltage Dielectric Constant Si-H Content N-H Content Stable H Bonding

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2000 Å/min Glass substrate  $\pm$  10% at 15mm EE 1.9  $\pm$  0.1  $\pm$  7E9D/cm<sup>2</sup> 300-600 Å/min (10:1 BHF) 5-8MV/cm 6-7 3-8E21/cm<sup>3</sup> 9-12E21/cm<sup>3</sup> Up to 600 °C

n+ a-Si-

(m) A K T

ITO

p-SiN

g-SiN SiO2

Gate Metal

S/D Metal

a-Si

## **Example of Gate SiNx - GH**



Film	DR	Stress	WER(6:1)	R.I.
	A/min	E9D/cm2	A/min	
GL	1300	C3.3	598	1.9
GH	1600	C2.7	485	1.93







## **Applications and Advantages**



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### **Process Performance**

**Deposition Rate** 

Thickness Non-Uniformity Stress Si-H Peak Si-H Peak FWHM 500-1000 Å/min E/S type 1500-3000 Å/min BCE type ± 10% at 15mm EE 6-9E9D/cm<sup>2</sup> (C) 2000 cm<sup>-1</sup> 95-100 cm<sup>-1</sup>





Film	DR	Stress	Peak Pos.
	A/min	E9D/cm2	cm-1
AL	500	C3.1	1994
AH	1200	C3.6	1994





# n+ a-Si



## **Applications and Advantages**



### **Process Performance**

Deposition Rate Thickness Non-Uniformity Stress Resistivity 500-1000 Å/min  $\pm$  10% at 15mm EE 6-9E9D/cm<sup>2</sup> (C)  $\leq$  200 Ω-cm



## Example of n+ a-Si

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Ell.	<u> </u>		-

Film	DR	Stress	Peak Pos.	Rsistivity
	A/min	E9D/cm2	cm-1	Ohm cm
n+ a-Si	650	C1.2	1994	56





## **Multi-layer Deposition**

## **Applications and Advantages**

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- Throughput improvement
- Particle reduction
- Yield improvement

Stress control Substrate temperature RF power Electrode spacing Gas flow ratio Processing pressure SiNx : +5E9 ~ -5E9 D/cm<sup>2</sup>



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#### **Two Chamber Process**

#### **Single Chamber Process**



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## p-SiN<sub>x</sub> Applications and Advantages

### Process Performance

Deposition Rate Thickness Non-Uniformity Refractive Index Stress Wet Etch Rate Breakdown Voltage Dielectric Constant Si-H Content N-H Content 2000 Å/min Glass substrate Gate Metal  $\pm$  10% at 15mm EE 1.9  $\pm$  0.1  $\pm$  7E9D/cm<sup>2</sup> 600-1200 Å/min (10:1 BHF) 5-8MV/cm 6-7 3-8E21/cm<sup>3</sup> 9-12E21/cm<sup>3</sup>

n+ a-Si

(m) A K T

p-SiN

g-SiN SiO<sub>2</sub> S/D Metal

a-Si





Film	DR	Stress	WER(6:1)	R.I.
	A/min	E9D/cm2	A/min	
Pas	1900	C2.4	1464	1.9





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## **Applications and Advantages**

SiO<sub>2</sub>



AKT

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### **Process Performance**

Deposition Rate Thickness Non-Uniformity Refractive Index Stress Wet Etch Rate Breakdown Voltage Dielectric Constant 500 to 3000 Å/min ± 10% at 15mm EE 1.46 ± 0.02 1-3E9D/cm<sup>2</sup> (C) 900-1800 Å/min (10:1 BHF) 5-10MV/cm 4-5





# Technologies of AKT

# E-beam Array Tester (EBT)



### **German Site**







History - long term continuation of team and technology

All key employees have stayed with the team under different company names since the early beginning, resources have continuously been added.

- **1982** Started in Siemens research with circuit board test technology
- **1991** First e-beam tester or PCB installed at Siemens Augsburg
- 1992 Group and technology transferred to ICT GmbH co-operation with MRS Technology inc.
- **1994/95** Co-operation with Hitachi to demonstrate test capability
- **1996 Prototype LCD matrix tester installed at ADT (Bosch)**
- **1997** Spun off as EBETECH and acquired by Etec
- 1998 Co-operation with DTI to demonstrate test capability relative to "charge sensing technology"
- 1999 First commercial systems installed in Korea at Samsung, SECS integration
- 2000 Etec acquired by Applied materials, EBT to continue operation within AKT organization as an Applied Materials Company, re-named AKT Electron Beam Technology,
- Present Continue to work within AKT, increasing installed base, next generations under development



- Yields cost savings:
  - Color filters and other materials by repair or scrap of array matrix
  - Several full production lots in case of process problem
  - Driver ICs in case cell test is skipped
  - Reduced production ramp







- Larger displays e.g. TV with higher cost of added components but demand to reduce overall cost
- Demand to drive cost down and take advantage of any cost saving possibility such as repair increasing demand for low or no pixel defects smaller pixels with higher risk for defects
- Short life time of each product requiring new product ramp up with initial yield problems



### **Electron Beam Technology**

- Use electron beam to address individual pixels for test and retest
  - Analyze emitted secondary electrons to sense pixel voltages
  - Inject current to charge each pixel voltage limited to transistor threshold voltage. No additional charging.



### **Test / Re-Test Strategy**





	data			
pixel	first test	re-test a		retest f
1	m1	a1		f1
2	m2	a2		f2
3	m3	a3		f3
4	m4	a4		f4

- Only the first test addresses all pixels, the re-test only those found in the first test
- Adds only low additional test time - only few pixels are retested (1000 x 10  $\mu$ s = 10 ms)
- Result data of all re-tests are evaluated for full characterization

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### Detectability

High S/N (signal/noise) ratio from vector-addressed (not raster scan) high voltage beam operation

Retest functionality offers compelling detection advantages with less impact on total throughput

### **Defect characterization**

Identify candidate defects with narrow testing thresholds

Perform additional tests <u>only</u> on candidate defects using new test recipes to isolate defect types and improve detection  $\rightarrow$  small impact on throughput

### **COO**

Throughput advantage of 20%-100% depending on substrate and panel size and pixel density  $\rightarrow$  reduce system number particularly for LCD TV fabs

Gun lifetime > 12 months

High reliability systems with uptime > 95% achieved



## <u>акт</u>

Gen.5 <u>AKT-15K</u> <u>EBT</u>

## Up to 1200x1300mm Glass Substrate





# **15K EBT Development Scope**

## <u>AKT</u>





## 2X Throughput By 2 Columns



70





## 25K/40K EBT System

#### Four Column & XY Table Concept





<u>AKT</u>





### Gen.6 and Gen.7 EBT System



### AKT-40K EBT System (25K System Same Architecture)

#### **Improvements:**

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- Mechanical TACT reduced by 25%
- 4 column operation reduces test time
- Vacuum exchange time cut by 50%
- Prober exchanger (<30 minutes)
- Improved stage isolation
- Vision system for improved L-mark detection
## **EBT Shipment History**

<u>AKT</u>







# Challenges and solutions to the

# large-size substrate processing



## Challenge of Large Size Equipment Developme 👸 AKT

- Have to Compete with Time
- How to maintain process uniformity within a "bed"
- Hardware reliability
  - Glass become larger and heavier
- How to maintain similar or even higher productivity despite of larger substrate



## **Critical Design Features for Large Substrate Sizes**

### **Example: Suspended Showerhead Diffuser Design**

#### **Challenges**

- Diffuser damage due to thermal expansion (up to 1 cm @ G.5 size)
- poor showerhead and substrate temperature uniformity

#### Solution: Suspended Showerhead Diffuser

- Reduces diffuser/substrate and susceptor / substrate temperature delta
- Accommodates diffuser thermal expansion



## Critical Design Features for Large Substrate Sizes AK

### **Example: Center Supported Showerhead Diffuser Design**

#### **Challenge**

 At larger generations, showerhead diffuser sag over time due to the heat and weight

#### Solution: Center Supported Showerhead Diffuser Design

- One or more adjustable supports at a center region to prevent diffuser sagging
- Allows control of diffuser profile to any shape (flat, concave, convex)





## **Hardware Performance**



Parallelism less than +/- 1mm over the whole electrode area

Tsusc = 340/350C Tsub (ave.) = 327C Range = 8C



### **Breaking the Physics Limit**



#### Plasma Surface Standing Wave Effect – making film center-dome non-uniformity



RF Frequency	Wavelength $\lambda_0$	Generation	Substrate Size	R (half diagonal)	$2.6(1/c)^{1/2}$ P					
(MHz)	(m)	Generation	(mm <sup>2</sup> )	(m)	2.0(L/S) K					
13.56	22.11	5	1100X1300	0.85	5.7					
27.12	11.05	6	1500X1850	1.19	8.0					
40.7	7.37	7	1870X2200	1.44	9.7					
60	5.00									
81.38	3.68	assuming spacing ~ 800 mil, $2L = 20$ mm, s ~ 1.5 mm								

Surface standing wave effects criteria :

 $\lambda_0 >> 2.6 (L / s)^{\frac{1}{2}} R$ 



## Critical Design Features for Large Substrate Sizes

#### **Example: HCG Showerhead Diffuser Design**

#### **Challenges**

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- At larger generations, CVD film properties becomes non-uniform with center dome thickness profile
- Root cause is the plasma density non-uniformity Standing Wave Effect

#### Solution: Hollow Cathode Gradient (HCG) Showerhead Diffuser Design

 Creating differentiated cone profiles and utilizing the Hollow Cathode Effect to counter the Standing Wave Effect



### **AKT-APX**<sub>L</sub> **PE-CVD** chamber achieved excellent film uniformity on Gen. 7 substrate and can be further scaled up beyond Gen. 7





ADY 2005 @ AKT

2005 ADY (Advanced Display of the Year) Display Equipment Award at FineTech, Japan



## Critical Design Features for Large Substrate Sizes

### **Example: Roller Bushing Lift Pin**

#### **Challenge**

• Sticking of lift pins causes glass breakage

#### Solution: Roller Bushing Lift Pin

• Guiding rollers totally eliminated lift pin sticking issue.

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### Vacuum Robot





**Liner Motion** 

- AKT-40K and 50K PECVD vacuum robot
  - Dual arm
  - Linear motion with link arm construction



### Vacuum Robot





Fig 1Production Robot #1 Cycle Test Condition (5/31/04)Fig 2Proto Type Cycling Condition(170K cycling test from 5/21 with 120% load, 80% speed)



## Vacuum Robot



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- Center
  - High friction pad and rest pad
- Front and Rear
  - Step pad











Fig. 3-2 Rear step pad (material: metal)







- SIMPLE & CLEAN
  - No Additional Actuator
  - No Vacuum Seal
  - No Lubrication/ No Bearing
- NO THROUGHPUT IMPACT



- PERFORMANCE
  - REQUIRED POSITIONING ACCURACY OF ATMOSPHERIC ROBOT
    Approx. +/- 3 mm from the calibrated DDSL load /unload position
    ALIGNMENT ACUURACY OF DDSL SUBSTRATE ALIGNMENT EQUIPMENT
    < +/- 0.5 mm</li>

Go to DDSL movie



### Variable Frequency RF Match



## - faster matching with higher reliability











### covering all process tuning range

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**Calculated Reflection Coefficient vs. RF Frequency for all Process Impedance** 



### and results in the same film properties



	DR	Stress	Peak Pos	WH/T
	A/min	E9D/cm <sup>2</sup>	cm⁻¹	arb unit
a-Si 1	1800	C 8.0	1994	0.56
a-Si 2	300	C 5.8	1994	0.50

	DR	Stress	Peak Pos	WH/T
	A/min	E9D/cm <sup>2</sup>	cm <sup>-1</sup>	arb unit
a-Si 1	1800	C 7.6	1994	0.56
a-Si 2	300	C 4.8	1995	0.46

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	Mobility	Vth	lon (A)	loff (A)	S
	V/cm <sup>2</sup> sec	V	@ Vg= 20V	@ Vg= -7V	V/dec
Conventional Matching	0.66	-1.0	3.1E-06	1.2E-11	0.80
Variable Freqency Matching	0.68	0.2	3.1E-06	2.0E-11	0.83



- Pre-move vacuum robot
- Dynamic substrate quantity control
- Synchronization of cleaning cycle
- Balance usage of process chamber



ΑΚΤ

Process	System	Prel (sec)	heat	CIn (sec)	Cycle (sub)	Depo (sec)	Vent (sec)	Pump (sec)	Slit V (sec)	PreMv (sec)	P/C # (Qty)	TPT (sub/hr)
<b>Passivation Layer</b>	DDSL	360	Hch	800	12	150	35	35	3	0	4	48.5
(SiN)		35	Pch	800	12	150+35	35	35	3	0	5	49.8
	TSSL	360	Hch	800	12	150	60	40	3	40	4	53.5
		35	Pch	800	12	150+35	60	40	3	40	5	61.0
Active Layer	DDSL	360	Hch	800	6	380	35	35	3	0	4	23.3
(g-SiN/a-Si/SiN)		35	Pch	800	6	380+35	35	35	3	0	5	30.5
	TSSL	360	Hch	800	6	380	60	40	3	40	4	24.0
		35	Pch	800	6	380+35	60	40	3	40	5	31.3

5 Pch (Preheat at Pch) and TSSL configuration improved >125~134% TPT









(approx. gross weight: 130 Ton)

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(B747-400 Uses 66.68 Tons of high strength Aluminum)

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Large system manufacturing requires improved skills and capabilities.

In 2004, AKT uses more aluminum than Boeing Co.

- materials procurement also becomes challenging.

### SUMMARY

 FPD era is already here. As the main growth engine of the TFT-LCD, LCD-TV shall thrive against the competitions from CRT & other FPD TVs.

 Accelerated system scale-up pace requires innovative solutions with fundamental understanding of the system & process to ensure the same or better film quality and system performance with <u>no</u> compromise at each new generation.

 Designing, engineering and manufacturing for the productivity – an overall approach to support the concept of <u>Production Worthiness</u>.



There are different kinds of fish...

Fish found in rivers wait for the current to bring food to them. They are passive and content with the flow of resources available to them. However, the fish found in lakes are constantly swimming around, looking for food. They consistently seek out opportunities and exhibit efficient behavior while doing so.

There are also different kinds of people...

The success of AKT is based upon a strong company culture personified by the "Hungry Fish". We encourage team work amongst our employees who are focused on our business, our products and the value our company offers to it's customers.





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